

Update on CCE results with very thin (50 μ m) Si detectors

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The effect of thickness on the CCE performances after irradiation is here investigated with measurements taken with a 50 μ m thick microstrip detectors irradiated at about 2.2 Neq cm⁻².

Primary author: CASSE, Gianluigi (University of Liverpool (GB))

Presenter: CASSE, Gianluigi (University of Liverpool (GB))

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